

Resource Summary Report

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FEI: nProber III System for Semiconductors

RRID:SCR_019894

Type: Tool

Proper Citation

FEI: nProber III System for Semiconductors (RRID:SCR_019894)

Resource Information

URL: <https://www.fei.com/products/efa/nprober-iii-for-semiconductors/>

Proper Citation: FEI: nProber III System for Semiconductors (RRID:SCR_019894)

Description: Electrical failure analysis system for semiconductors with fault localization and transistor characterization that allows users to characterize individual transistor performance down to 7nm node.

Resource Type: instrument resource

Keywords: FEI, EFA System, Instrument Equipment, USEDit,

Availability: Commercially available

Resource Name: FEI: nProber III System for Semiconductors

Resource ID: SCR_019894

Alternate IDs: Model_Number_nProber_III

Record Creation Time: 20220129T080347+0000

Record Last Update: 20260912T195924+0000

Ratings and Alerts

No rating or validation information has been found for FEI: nProber III System for Semiconductors.

No alerts have been found for FEI: nProber III System for Semiconductors.

Data and Source Information

Source: [SciCrunch Registry](#)

Usage and Citation Metrics

We have not found any literature mentions for this resource.